

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/516,940	FUNAKOSHI ET AL.
	<b>Examiner</b> Jafar Parsa	<b>Art Unit</b> 1621

**SEARCHED**

<b>INTERFERENCE SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
560	205	1/7/2007	JP
570	139, 172	1/7/2007	JP